

CHANGE NOTIFICATION



NOW PART OF



Analog Devices, Inc.
1630 McCarthy Blvd., Milpitas, CA 95035-7417
(408) 432-1900

May 24, 2017

Dear Sir/Madam:

PCN#052417

Subject: Notification of Qualification of Revised Substrate and Alternate Components for the LTM4624 and LTM4625 μ Module Regulators

This notice is to inform you that Analog Devices, Inc. Milpitas, California has made minor changes to the LTM4624 and LTM4625 μ Module regulators as follows:

1. Remove a substrate trace from under a capacitor to reduce sensitivity to moisture during the PCB assembly reflow process
2. Qualify alternate source diode and inductor to provide greater supply assurance and reduced product lead time

There is no effect on customer applications since there is no change in form, fit, function or quality of the product. The new bill of materials has been qualified by performing characterization over the full operating junction temperature range and through rigorous engineering bench evaluations. Electrical and thermal performances are identical. In addition, standard qualification tests were successfully completed, including power cycling, thermal shock, temperature cycling and high temperature operating life. The qualification results summary is attached.

The list of part numbers affected:

LTM4624EY#PBF
LTM4624IY#PBF
LTM4624IY
LTM4624EY#2MHPBF
LTM4625EY#PBF
LTM4625IY
LTM4625IY#3KK
LTM4625IY#3KL
LTM4625IY#3LB
LTM4625IY#PBF

Analog Devices will accept requests for revised samples within 30 days of the date of this notification. If we don't hear back from your company within this 30 day period, we will consider acceptance of this Change Notice by July 24, 2017. After this time, Analog Devices may not be able to accommodate customer requests to receive older product. Production shipments of product incorporating the new substrate and alternate source components will begin no sooner than July 24, 2017.

Should you have any further questions, please feel free to contact me at 408-432-1900 ext. 2077, or by E-mail JASON.HU@ANALOG.COM.

Sincerely,

Jason Hu
Quality Assurance Engineer

QUALIFICATION DATA					
LTM4624 / LTM4625 Revised Substrate and Alternate Component					
5/23/2017					
• J-STD-020 MSL3 PRECONDITIONING: 192h +30°C/60% R.H., 3x REFLOW AT +250°C PEAK					
DEVICE TYPE	SAMPLE SIZE	DATE CODE RANGE			NUMBER OF FAILURES
LTM4624	231	1648			0
LTM4625	462	1636~1710			0
	693	1,648			0
• EXTENDED MSL 3+ PRECONDITIONING: 216h +30°C/60% R.H., 3x REFLOW AT +250°C PEAK					
DEVICE TYPE	SAMPLE SIZE	DATE CODE RANGE			NUMBER OF FAILURES
LTM4624	77	1648			0
LTM4625	70	1636~1710			0
	147	1,648			0
• UNBIASED HIGHLY ACCELERATED STRESS TEST (U-HAST) AT +130°C/85% R.H. ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	DATE CODE RANGE	HOURS ON HAST	DEVICE HOURS AT +130°C	NUMBER OF FAILURES
LTM4624	77	1648	96	7,392	0
LTM4625	77	1636	192	14,784	0
	154			22,176	0
• TEMP CYCLE FROM -55°C TO +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	DATE CODE RANGE	CYCLES ON TC	DEVICE CYCLES	NUMBER OF FAILURES
LTM4624	77	1648	1,000	77,000	0
LTM4625	77	1636	1,000	77,000	0
	154			154,000	0
• THERMAL SHOCK FROM -55°C TO +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	DATE CODE RANGE	CYCLES ON TS	DEVICE CYCLES	NUMBER OF FAILURES
LTM4624	76	1648	1,000	76,000	0
LTM4625	77	1636	1,000	77,000	0
	153			153,000	0
• HIGH TEMPERATURE STORAGE AT 150°C					
DEVICE TYPE	SAMPLE SIZE	DATE CODE RANGE	HOURS ON HTS	DEVICE HOURS AT +150°C	NUMBER OF FAILURES
LTM4624	77	1648	1,000	77,000	0
LTM4625	77	1636	1,000	77,000	0
	154			154,000	0
(1) Environmental stress are preceded by JEDEC Level 3 Preconditioning: 192h 30°C/60% R.H. plus 3x Reflow at 250°C.					

Confidential Statement
This change notice is for ADI's customers only.
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